- Low Supply Voltage Range 1.8 V 3.6 V
- Ultralow-Power Consumption:
  - Active Mode: 200 μA at 1 MHz, 2.2 V
  - Standby Mode: 0.7 μA
  - Off Mode (RAM Retention): 0.1  $\mu$ A
- Five Power Saving Modes
- Wake-Up From Standby Mode in less than 6 μs
- 16-Bit RISC Architecture, 125 ns Instruction Cycle Time
- Basic Clock Module Configurations:
  - Various Internal Resistors
  - Single External Resistor
  - 32-kHz Crystal
  - High Frequency Crystal
  - Resonator
  - External Clock Source
- 16-Bit Timer\_A With Three Capture/Compare Registers
- 10-Bit, 200-ksps A/D Converter With Internal Reference, Sample-and-Hold, Autoscan, and Data Transfer Controller
- Serial Communication Interface (USART0)
   With Software-Selectable Asynchronous
   UART or Synchronous SPI
   (MSP430x12x2 Only)

- Serial Onboard Programming, No External Programming Voltage Needed Programmable Code Protection by Security Fuse
- Supply Voltage Brownout Protection
- MSP430x11x2 Family Members Include:
   MSP430F1122: 4KB + 256B Flash Memory
   256B RAM
  - MSP430F1132: 8KB + 256B Flash Memory 256B RAM

Available in 20-Pin Plastic SOWB, 20-Pin Plastic TSSOP and 32-Pin QFN Packages

- MSP430x12x2 Family Members Include: MSP430F1222: 4KB + 256B Flash Memory 256B RAM
  - MSP430F1232: 8KB + 256B Flash Memory 256B RAM

Available in 28-Pin Plastic SOWB, 28-Pin Plastic TSSOP, and 32-Pin QFN Packages

 For Complete Module Descriptions, See the MSP430x1xx Family User's Guide, Literature Number SLAU049

### description

The Texas Instruments MSP430 family of ultralow-power microcontrollers consist of several devices featuring different sets of peripherals targeted for various applications. The architecture, combined with five low power modes is optimized to achieve extended battery life in portable measurement applications. The device features a powerful 16-bit RISC CPU, 16-bit registers, and constant generators that attribute to maximum code efficiency. The digitally controlled oscillator (DCO) allows wake-up from low-power modes to active mode in less than 6µs.

The MSP430x11x2 and MSP430x12x2 series are ultralow-power mixed signal microcontrollers with a built-in 16-bit timer, 10-bit A/D converter with integrated reference and data transfer controller (DTC) and fourteen or twenty-two I/O pins. In addition, the MSP430x12x2 series microcontrollers have built-in communication capability using asynchronous (UART) and synchronous (SPI) protocols.

Digital signal processing with the 16-bit RISC performance enables effective system solutions such as glass breakage detection with signal analysis (including wave digital filter algorithm). Another area of application is in stand-alone RF sensors.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

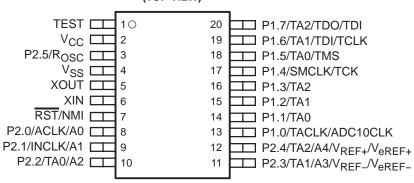


#### **AVAILABLE OPTIONS**

		PACKAGED DEVICES						
TA	PLASTIC 20-PIN SOWB (DW)	PLASTIC 20-PIN TSSOP (PW)	PLASTIC 28-PIN SOWB (DW)	PLASTIC 28-PIN TSSOP (PW)	PLASTIC 32-PIN QFN (RHB)			
-40°C to 85°C	MSP430F1122IDW MSP430F1132IDW	MSP430F1122IPW MSP430F1132IPW	MSP430F1222IDW MSP430F1232IDW	MSP430F1222IPW MSP430F1232IPW	MSP430F1122IRHB MSP430F1132IRHB MSP430F1222IRHB MSP430F1232IRHB			

# pin designation, MSP430x11x2 (see Note)

#### **DW or PW PACKAGE** (TOP VIEW)

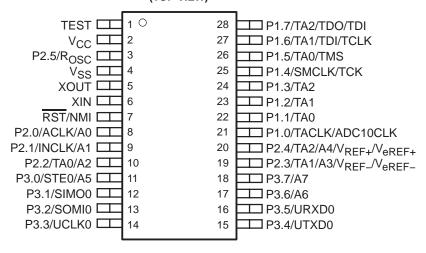


### **RHB PACKAGE** (TOP VIEW) P1.6/TA1/TDI/TCLK P1.5/TA0/TMS P1.4/SMCLK/TCk 31 30 29 28 27 26 <sub>24</sub> P1.3/TA2 $V_{SS}$ XOUT 2 23 🗖 P1.2/TA1 XIN 13 22 P1.1/TA0 21 P1.0/TACLK/ADC10CLK NC P4 RST/NMI 5 20 **I** NC 19 P2.4/TA2/A4/V<sub>REF+</sub>/V<sub>eREF+</sub> P2.0/ACLK/A0 6 18 🗖 P2.3/TA1/A3/V<sub>REF</sub>\_/V<sub>eREF</sub>\_ P2.1/INCLK/A1 P2.2/TA0/A2 17 🗖 NC **1**8

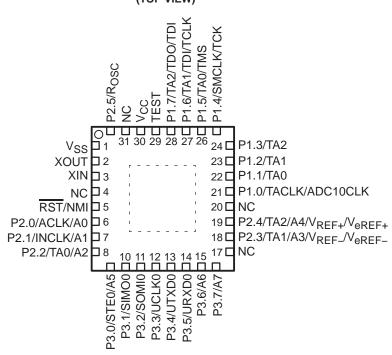
Note: It is recommended that all NC pins be connected to VSS to avoid floating nodes, otherwise increased current consumption may occur. Power pad not internally connected.

# pin designation, MSP430x12x2 (see Note)

# DW or PW PACKAGE (TOP VIEW)

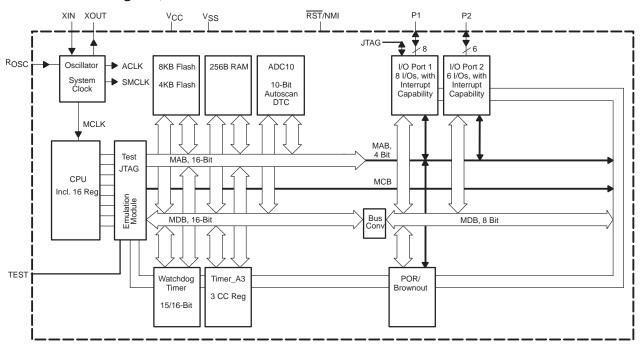


#### RHB PACKAGE (TOP VIEW)

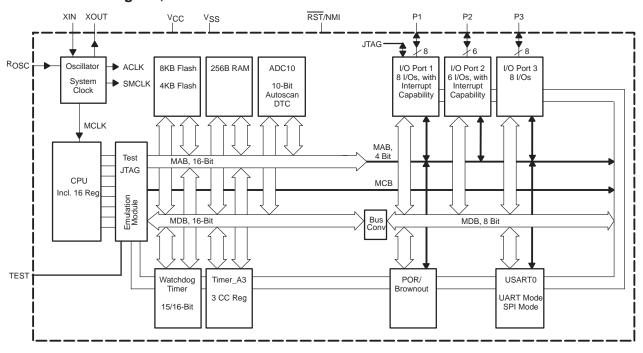


Note: It is recommended that all NC pins be connected to VSS to avoid floating nodes, otherwise increased current consumption may occur. Power pad not internally connected.

# functional block diagram, MSP430x11x2



# functional block diagram, MSP430x12x2



# Terminal Functions, MSP430x11x2

TERMINAL  NAME DW & PW RHB					
		1/0	DESCRIPTION		
P1.0/TACLK/ ADC10CLK	13	21	I/O	General-purpose digital I/O pin/Timer_A, clock signal TACLK input/conversion clock—10-bit ADC	
P1.1/TA0	14	22	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0A input, compare: Out0 output/BSL transmit	
P1.2/TA1	15	23	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI1A input, compare: Out1 output	
P1.3/TA2	16	24	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI2A input, compare: Out2 output	
P1.4/SMCLK/TCK	17	25	I/O	General-purpose digital I/O pin/SMCLK signal output/test clock, input terminal for device programming and test	
P1.5/TA0/TMS	18	26	I/O	General-purpose digital I/O pin/Timer_A, compare: Out0 output/test mode select, input terminal for device programming and test	
P1.6/TA1/TDI/TCLK	19	27	I/O	General-purpose digital I/O pin/Timer_A, compare: Out1 output/test data input terminal or test clock input	
P1.7/TA2/TDO/TDI <sup>†</sup>	20	28	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/test data output terminal or data input during programming	
P2.0/ACLK/A0	8	6	I/O	General-purpose digital I/O pin/ACLK output/analog input to 10-bit ADC input A0	
P2.1/INCLK/A1	9	7	I/O	General-purpose digital I/O pin/Timer_A, clock signal at INCLK/analog input to 10-bit ADC input A1	
P2.2/TA0/A2	10	8	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0B input, compare: Out0 output/analog input to 10-bit ADC input A2/BSL receive	
P2.3/TA1/A3/V <sub>REF</sub> _/ V <sub>e</sub> REF_	11	18	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI1B input, compare: Out1 output/analog input to 10-bit ADC input A3/negative reference voltage terminal.	
P2.4/TA2/A4/V <sub>REF+</sub> / V <sub>e</sub> REF+	12	19	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/analog input to 10-bit ADC input A4/I/O of positive reference voltage terminal	
P2.5/ROSC	3	32	I/O	General-purpose digital I/O pin/Input for external resistor that defines the DCO nominal frequency	
RST/NMI	7	5	ı	Reset or nonmaskable interrupt input	
TEST	1	29	I	Selects test mode for JTAG pins on P1.x	
Vcc	2	30		Supply voltage	
VSS	4	1		Ground reference	
XIN	6	3	I	Input terminal of crystal oscillator	
XOUT	5	2	0	Output terminal of crystal oscillator	
NC	NA	4,9-16, 17,20,31		No connect. Recommended connection to V <sub>SS</sub> to avoid floating nodes, otherwise increased current consumption may occur.	

<sup>†</sup>TDO or TDI is selected via JTAG instruction.

# Terminal Functions, MSP430x12x2

TERMINAL					
NAME	DW & PW	RHB	1/0	DESCRIPTION	
P1.0/TACLK/ ADC10CLK	21	21	I/O	General-purpose digital I/O pin/Timer_A, clock signal TACLK input/conversion clock—10-bit ADC	
P1.1/TA0	22	22	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0A input, compare: Out0 output/BSL transmit	
P1.2/TA1	23	23	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI1A input, compare: Out1 output	
P1.3/TA2	24	24	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI2A input, compare: Out2 output	
P1.4/SMCLK/TCK	25	25	I/O	General-purpose digital I/O pin/SMCLK signal output/test clock, input terminal for device programming and test	
P1.5/TA0/TMS	26	26	I/O	General-purpose digital I/O pin/Timer_A, compare: Out0 output/test mode select, input terminal for device programming and test	
P1.6/TA1/TDI/TCLK	27	27	I/O	General-purpose digital I/O pin/Timer_A, compare: Out1 output/test data input terminal or test clock input	
P1.7/TA2/TDO/TDI†	28	28	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/test data output terminal or data input during programming	
P2.0/ACLK/A0	8	6	I/O	General-purpose digital I/O pin/ACLK output/analog input to 10-bit ADC input A0	
P2.1/INCLK/A1	9	7	I/O	General-purpose digital I/O pin/Timer_A, clock signal at INCLK/analog input to 10-bit ADC input A1	
P2.2/TA0/A2	10	8	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI0B input, compare: Out0 output/analog input to 10-bit ADC input A2/BSL receive	
P2.3/TA1/A3/V <sub>REF</sub> _/ V <sub>e</sub> REF_	19	18	I/O	General-purpose digital I/O pin/Timer_A, capture: CCI1B input, compare: Out1 output/analog input to 10-bit ADC input A3/negative reference voltage terminal.	
P2.4/TA2/A4/V <sub>REF+</sub> / V <sub>eREF+</sub>	20	19	I/O	General-purpose digital I/O pin/Timer_A, compare: Out2 output/analog input to 10-bit ADC input A4/I/O of positive reference voltage terminal	
P2.5/R <sub>OSC</sub>	3	32	I/O	General-purpose digital I/O pin/Input for external resistor that defines the DCO nominal frequency	
P3.0/STE0/A5	11	9	I/O	General-purpose digital I/O pin/slave transmit enable—USART0/SPI mode/analog input to 10-bit ADC input A5	
P3.1/SIMO0	12	10	I/O	General-purpose digital I/O pin/slave in/master out of USART0/SPI mode	
P3.2/SOMI0	13	11	I/O	General-purpose digital I/O pin/slave out/master in of USART0/SPI mode	
P3.3/UCLK0	14	12	I/O	General-purpose digital I/O pin/external clock input—USART0/UART or SPI mode, clock output—USART0/SPI mode clock input	
P3.4/UTXD0	15	13	I/O	General-purpose digital I/O pin/transmit data out—USART0/UART mode	
P3.5/URXD0	16	14	I/O	General-purpose digital I/O pin/receive data in—USART0/UART mode	
P3.6/A6	17	15	I/O	General-purpose digital I/O pin/analog input to 10-bit ADC input A6	
P3.7/A7	18	16	I/O	General-purpose digital I/O pin/analog input to 10-bit ADC input A7	
RST/NMI	7	5	ı	Reset or nonmaskable interrupt input	
TEST	1	29	ı	Selects test mode for JTAG pins on P1.x	
VCC	2	30		Supply voltage	
V <sub>SS</sub>	4	1		Ground reference	
XIN	6	3	I	Input terminal of crystal oscillator	
XOUT	5	2	0	Output terminal of crystal oscillator	
NC	NA	4,17, 20,31		No connect. Recommended connection to V <sub>SS</sub> to avoid floating nodes, otherwise increased current consumption may occur.	

<sup>†</sup>TDO or TDI is selected via JTAG instruction.



#### short-form description

#### **CPU**

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

#### instruction set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. Table 1 shows examples of the three types of instruction formats; the address modes are listed in Table 2.



**Table 1. Instruction Word Formats** 

Dual operands, source-destination	e.g. ADD R4,R5	R4 + R5> R5
Single operands, destination only	e.g. CALL R8	PC>(TOS), R8> PC
Relative jump, un/conditional	e.g. JNE	Jump-on-equal bit = 0

**Table 2. Address Mode Descriptions** 

ADDRESS MODE	s	D	SYNTAX	EXAMPLE	OPERATION
Register	•	•	MOV Rs,Rd	MOV R10,R11	R10> R11
Indexed	•	•	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5)> M(6+R6)
Symbolic (PC relative)	•	•	MOV EDE,TONI		M(EDE)> M(TONI)
Absolute	•	•	MOV &MEM,&TCDAT		M(MEM)> M(TCDAT)
Indirect	•		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10)> M(Tab+R6)
Indirect autoincrement	•		MOV @Rn+,Rm	MOV @R10+,R11	M(R10)> R11 R10 + 2> R10
Immediate	•		MOV #X,TONI	MOV #45,TONI	#45> M(TONI)

NOTE: S = source D = destination



# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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#### operating modes

The MSP430 has one active mode and five software selectable low-power modes of operation. An interrupt event can wake up the device from any of the five low-power modes, service the request and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode AM;
  - All clocks are active
- Low-power mode 0 (LPM0);
  - CPU is disabled ACLK and SMCLK remain active. MCLK is disabled
- Low-power mode 1 (LPM1);
  - CPU is disabled
     ACLK and SMCLK remain active. MCLK is disabled
     DCO's dc-generator is disabled if DCO not used in active mode
- Low-power mode 2 (LPM2);
  - CPU is disabled
     MCLK and SMCLK are disabled
     DCO's dc-generator remains enabled
     ACLK remains active
- Low-power mode 3 (LPM3);
  - CPU is disabled MCLK and SMCLK are disabled DCO's dc-generator is disabled ACLK remains active
- Low-power mode 4 (LPM4);
  - CPU is disabled
     ACLK is disabled
     MCLK and SMCLK are disabled
     DCO's dc-generator is disabled
     Crystal oscillator is stopped



#### interrupt vector addresses

The interrupt vectors and the power-up starting address are located in the memory with an address range of 0FFFFh-0FFE0h. The vector contains the 16-bit address of the appropriate interrupt handler instruction

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power-up, external reset, watchdog	WDTIFG (see Note1) KEYV (see Note 1)	Reset	0FFFEh	15, highest
NMI, oscillator fault, flash memory access violation	NMIIFG (see Notes 1 and 4) OFIFG (see Notes 1 and 4) ACCVIFG (see Notes 1 and 4)	(Non)-maskable, (Non)-maskable, (Non)-maskable	0FFFCh	14
			0FFFAh	13
			0FFF8h	12
			0FFF6h	11
Watchdog timer	WDTIFG	Maskable	0FFF4h	10
Timer_A	TACCR0 CCIFG (see Note 2)	Maskable	0FFF2h	9
Timer_A	TACCR1 and TACCR2 CCIFGs, TAIFG (see Notes 1 and 2)	Maskable	0FFF0h	8
USART0 receive (see Note 5)	URXIFG0	Maskable	0FFEEh	7
USART0 transmit (see Note 5)	UTXIFG0	Maskable	0FFECh	6
ADC10	ADC10IFG	Maskable	0FFEAh	5
			0FFE8h	4
I/O Port P2 (eight flags – see Note 3)	P2IFG.0 to P2IFG.7 (see Notes 1 and 2)	Maskable	0FFE6h	3
I/O Port P1 (eight flags)	P1IFG.0 to P1IFG.7 (see Notes 1 and 2)	Maskable	0FFE4h	2
			0FFE2h	1
			0FFE0h	0, lowest

- NOTES: 1. Multiple source flags
  - 2. Interrupt flags are located in the module
  - 3. There are eight Port P2 interrupt flags, but only six Port P2 I/O pins (P2.0-5) are implemented on the '11x2 and '12x2 devices.
  - 4. (Non)-maskable: the individual interrupt enable bit can disable an interrupt event, but the general interrupt enable cannot.
  - 5. USART0 is implemented in MSP430x12x2 only.

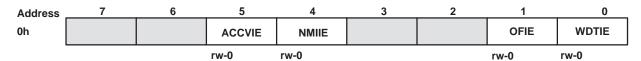
# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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# special function registers

Most interrupt and module enable bits are collected into the lowest address space. Special function register bits that are not allocated to a functional purpose are not physically present in the device. Simple software access is provided with this arrangement.

#### interrupt enable 1 and 2



WDTIE: Watchdog Timer interrupt enable. Inactive if watchdog mode is selected. Active if Watchdog Timer

is configured in interval timer mode.

OFIE: Oscillator fault enable

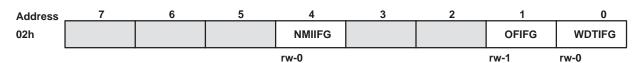
NMIIE: (Non)maskable interrupt enable

Flash access violation interrupt enable ACCVIE:



URXIEO: USARTO, UART, and SPI receive-interrupt enable (MSP430x12x2 devices only) UTXIEO: USARTO, UART, and SPI transmit-interrupt enable (MSP430x12x2 devices only)

### interrupt flag register 1 and 2



WDTIFG: Set on Watchdog Timer overflow (in watchdog mode) or security key violation.

Reset on V<sub>CC</sub> power-up or a reset condition at RST/NMI pin in reset mode.

OFIFG: Flag set on oscillator fault Set via RST/NMI-pin NMIIFG:



URXIFG0: USART0, UART, and SPI receive flag (MSP430x12x2 devices only) UTXIFG0: USART0, UART, and SPI transmit flag (MSP430x12x2 devices only)



# module enable registers 1 and 2

Address	7	6	5	4	3	2	1	0
04h								
Address	7	6	5	4	3	2	1	0
05h							UTXE0	URXE0 USPIE0
					-		rw-0	rw-0

URXE0: USART0, UART mode receive enable (MSP430x12x2 devices only)
UTXE0: USART0, UART mode transmit enable (MSP430x12x2 devices only)

USPIE0: USARTO, SPI mode transmit and receive enable (MSP430x12x2 devices only)

**Legend rw:** Bit can be read and written.

rw-0: Bit can be read and written. It is reset by PUC

SFR bit is not present in device.

# memory organization

	MSP430F1122 MSP430F1222		MSP430F1132 MSP430F1232	
FFFFh FFE0h	Int. Vector	FFFFh FFE0h	Int. Vector	
FFDFh F000h	4 KB Flash Segment0-7	FFDFh	8 KB Flash Segment0–15	Main Memory
		E000h		
10FFh	2×128B Flash	10FFh	2 × 128B Flash	Information Memory
1000h	SegmentA,B	1000h 0FFFh	SegmentA,B	Memory
0FFFh	1 KB	UFFFN	1 KB	
0C00h	Boot ROM	0C00h	Boot ROM	
02FFh 0200h	256B RAM	02FFh 0200h	256B RAM	
01FFh 0100h	16b Per.	01FFh 0100h	16b Per.	
00FFh 0010h	8b Per.	00FFh 0010h	8b Per.	
000Fh 0000h	SFR	000Fh 0000h	SFR	
000011		000011		

# bootstrap loader (BSL)

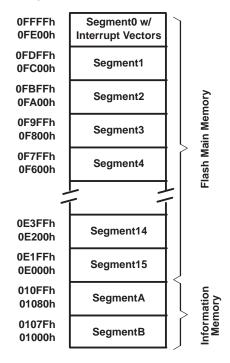
The MSP430 bootstrap loader (BSL) enables users to program the flash memory or RAM using a UART serial interface. Access to the MSP430 memory via the BSL is protected by user-defined password. For complete description of the features of the BSL and its implementation, see the Application report *Features of the MSP430 Bootstrap Loader*, Literature Number SLAA089.

BSL Function	MSP430x11x2 DW & PW Package (20 Pins)	MSP430x12x2 DW & PW Package (28 Pins)	MSP430x11x2/12x2 RHB Package (32 Pins)
Data Transmit	14 - P1.1	22 - P1.1	22 - P1.1
Data Receive	10 - P2.2	10 - P2.2	8 - P2.2

# flash memory

The flash memory can be programmed via the JTAG port, the bootstrap loader, or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and two segments of information memory (A and B) of 128 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A and B can be erased individually, or as a group with segments 0-n.
   Segments A and B are also called information memory.
- New devices may have some bytes programmed in the information memory (needed for test during manufacturing). The user should perform an erase of the information memory prior to the first use.



NOTE: All segments not implemented on all devices.



# peripherals

Peripherals are connected to the CPU through data, address, and control busses and can be handled using all instructions. For complete module descriptions, see the MSP430x1xx Family User's Guide, literature number SLAU049.

# oscillator and system clock

The clock system in the MSP430x11x2 and MSP430x12x2 devices is supported by the basic clock module that includes support for a 32768-Hz watch crystal oscillator, an internal digitally-controlled oscillator (DCO) and a high frequency crystal oscillator. The basic clock module is designed to meet the requirements of both low system cost and low-power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 6 μs. The basic clock module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from a 32768-Hz watch crystal or a high frequency crystal.
- Main clock (MCLK), the system clock used by the CPU.
- Sub-Main clock (SMCLK), the sub-system clock used by the peripheral modules.

### digital I/O

There are 3 8-bit I/O ports implemented—ports P1, P2, and P3 (only six port P2 I/O signals are available on external pins; port P3 is implemented only on 'x12x2 devices):

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt conditions is possible.
- Edge-selectable interrupt input capability for all the eight bits of ports P1 and six bits of port P2.
- Read/write access to port-control registers is supported by all instructions.

#### NOTE:

Six bits of port P2, P2.0 to P2.5, are available on external pins, but all control and data bits for port P2 are implemented. Port P3 has no interrupt capability. Port P3 is implemented in MSP430x12x2 only.

#### brownout

The brownout circuit is implemented to provide the proper internal reset signal to the device during power on and power off.

### watchdog timer

The primary function of the watchdog timer (WDT) module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be configured as an interval timer and can generate interrupts at selected time intervals.

#### USARTO (MSP430x12x2 Only)

The MSP430x12x2 devices have one hardware universal synchronous/asynchronous receive transmit (USART0) peripheral module that is used for serial data communication. The USART supports synchronous SPI (3 or 4 pin) and asynchronous UART communication protocols, using double-buffered transmit and receive channels.

#### ADC<sub>10</sub>

The ADC10 module supports fast, 10-bit analog-to-digital conversions. The module implements a 10-bit SAR core, sample select control, reference generator and data transfer controller, or DTC, for automatic conversion result handling allowing ADC samples to be converted and stored without any CPU intervention.



# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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# timer\_A3

Timer\_A3 is a 16-bit timer/counter with three capture/compare registers. Timer\_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer\_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

			7	Timer_A3 Signa	al Connectio	ns			
In	out Pin Num	nber					Out	mber	
DW a	nd PW	RHB	Device Input	Module	Module	Module Output	DW a	nd PW	RHB
'11x2 20-Pin	'12x2 28-Pin	'11x2/12x2 32-Pin	Signal	Input Name		Signal	'11x2 20-Pin	'12x2 28-Pin	'11x2/12x2 32-Pin
13 - P1.0	21 - P1.0	21 - P1.0	TACLK	TACLK					
			ACLK	ACLK	<b>_</b>				
			SMCLK	SMCLK	Timer	NA			
9 - P2.1	9 - P2.1	7 - P2.1	INCLK	INCLK					
14 - P1.1	22 - P1.1	22 - P1.1	TA0	CCI0A		TA0	14 - P1.1	22 - P1.1	22 - P1.1
10 - P2.2	10 - P2.2	8 - P2.2	TA0	CCI0B	0000		18 - P1.5	26 - P1.5	26 - P1.5
			DV <sub>SS</sub>	GND	CCR0		10 - P2.2	10 - P2.2	8 - P2.2
			DV <sub>CC</sub>	Vcc			ADC10 Internal		
15 - P1.2	23 - P1.2	23 - P1.2	TA1	CCI1A			15 - P1.2	23 - P1.2	23 - P1.2
11 - P2.3	19 - P2.3	18 - P2.3	TA1	CCI1B	0004	T. 4	19 - P1.6	27 - P1.6	27 - P1.6
			DVSS	GND	CCR1	TA1	11 - P2.3	19 - P2.3	18 - P2.3
			DVCC	Vcc			ADC10 Interna		nal
16 - P1.3	24 - P1.3	24 - P1.3	TA2	CCI2A			16 - P1.3	24 - P1.3	24 - P1.3
			ACLK (internal)	CCI2B	0000	TA 0	20 - P1.7	28 - P1.7	28 - P1.7
			DVSS	GND	CCR2	TA2	12 - P2.4	20 - P2.4	19 - P2.4
			DV <sub>CC</sub>	Vcc			P	ADC10 Interi	nal

# peripheral file map

PERIPHERALS WITH WORD ACCESS								
ADC10	ADC data transfer start address ADC memory ADC control register 1 ADC control register 0 ADC analog enable ADC data transfer control register 1 ADC data transfer control register 0	ADC10SA ADC10MEM ADC10CTL1 ADC10CTL0 ADC10AE ADC10DTC1 ADC10DTC0	1BCh 1B4h 1B2h 1B0h 04Ah 049h 048h					
Timer_A	Reserved Reserved Reserved Reserved Capture/compare register Capture/compare register Capture/compare register Timer_A register Reserved Reserved Reserved Reserved Reserved Reserved	TACCR2 TACCR1 TACCR0 TAR	017Eh 017Ch 017Ah 0178h 0176h 0174h 0172h 0170h 016Eh 016Ch 016Ah 0168h					
	Capture/compare control Capture/compare control Capture/compare control Timer_A control Timer_A interrupt vector	TACCTL2 TACCTL1 TACCTL0 TACTL TAIV	0166h 0164h 0162h 0160h 012Eh					
Flash Memory	Flash control 3 Flash control 2 Flash control 1	FCTL3 FCTL2 FCTL1	012Ch 012Ah 0128h					
Watchdog	Watchdog/timer control	WDTCTL	0120h					
	PERIPHERALS WITH BYTE ACCESS							
USART0 (in MSP430x12x2 only)	Transmit buffer Receive buffer Baud rate Baud rate Modulation control Receive control Transmit control USART control	UOTXBUF UORXBUF UOBR1 UOBR0 UOMCTL UORCTL UOTCTL UOCTL	077h 076h 075h 074h 073h 072h 071h 070h					
Basic Clock	Basic clock sys. control2 Basic clock sys. control1 DCO clock freq. control	BCSCTL2 BCSCTL1 DCOCTL	058h 057h 056h					
Port P2	Port P2 selection Port P2 interrupt enable Port P2 interrupt edge select Port P2 interrupt flag Port P2 direction Port P2 output Port P2 input	P2SEL P2IE P2IES P2IFG P2DIR P2OUT P2IN	02Eh 02Dh 02Ch 02Bh 02Ah 029h 028h					
Port P1	Port P1 selection Port P1 interrupt enable Port P1 interrupt edge select Port P1 interrupt flag Port P1 direction Port P1 output Port P1 input	P1SEL P1IE P1IES P1IFG P1DIR P1OUT P1IN	026h 025h 024h 023h 022h 021h 020h					



# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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# peripheral file map (continued)

PERIPHERALS WITH BYTE ACCESS (CONTINUED)							
Port P3 (in MSP430x12x2 only)	Port P3 selection Port P3 direction Port P3 output Port P3 input	P3SEL P3DIR P3OUT P3IN	01Bh 01Ah 019h 018h				
Special Function	Module enable2 Module enable1 SFR interrupt flag2 SFR interrupt flag1 SFR interrupt enable2 SFR interrupt enable1	ME2 ME1 IFG2 IFG1 IE2 IE1	005h 004h 003h 002h 001h 000h				

# absolute maximum ratings†

Voltage applied at V <sub>CC</sub> to V <sub>SS</sub>	
Voltage applied to any pin (see Note)	0.3 V to V <sub>CC</sub> + 0.3 V
Diode current at any device terminal	±2 mA
Storage temperature, T <sub>sta</sub> (unprogrammed device)	–55°C to 150°C
Storage temperature, T <sub>sta</sub> (programmed device)	–40°C to 85°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE: All voltages referenced to VSS. The JTAG fuse-blow voltage, VFB, is allowed to exceed the absolute maximum rating. The voltage is applied to the TEST pin when blowing the JTAG fuse.

# recommended operating conditions

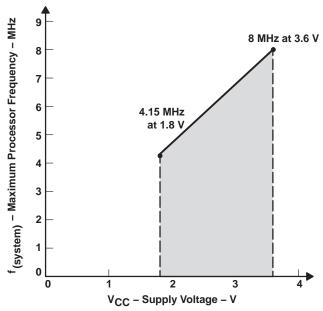
			MIN	NOM	MAX	UNITS
Supply voltage during program execution, \	CC (see Note 1)	MSP430F11x2	1.8		3.6	V
Supply voltage during program/erase flash memory, V <sub>CC</sub>		MSP430F12x2	2.7		3.6	V
Supply voltage, VSS				0		V
Operating free-air temperature range, TA		MSP430F11x2 MSP430F12x2	-40		85	°C
	LF mode selected, XTS=0	Watch crystal		32768		Hz
LFXT1 crystal frequency, f <sub>(LFXT1)</sub> (see Note 2)	VT4 calcated made VTC 4	Ceramic resonator	450		8000	kHz
(See Note 2)	XT1 selected mode, XTS=1	Crystal	1000		3.6 3.6 0 85 2768 8000 8000 4.15	KHZ
		V <sub>CC</sub> = 1.8 V, MSP430F11x2 MSP430F12x2	dc		4.15	
Processor frequency f <sub>(system)</sub> (MCLK sign	ai)	V <sub>CC</sub> = 3.6 V, MSP430F11x2 MSP430F12x2	dc		8	MHz

- NOTES: 1. The LFXT1 oscillator in LF-mode requires a resistor of 5.1 M $\Omega$  from XOUT to VSS when VCC <2.5 V. The LFXT1 oscillator in XT1-mode accepts a ceramic resonator or a crystal frequency of 4 MHz at VCC  $\geq$  2.2 V. The LFXT1 oscillator in XT1-mode accepts a ceramic resonator or a crystal frequency of 8 MHz at VCC  $\geq$  2.8 V.
  - The LFXT1 oscillator in LF-mode requires a watch crystal.
     The LFXT1 oscillator in XT1-mode accepts a ceramic resonator or a crystal.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

# MSP430F11x2 and MSP430F12x2 Devices



NOTE: Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum V<sub>CC</sub> of 2.7 V.

Figure 1. Frequency vs Supply Voltage

# supply current (into V<sub>CC</sub>) excluding external current

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
		$T_A = -40^{\circ}C + 85^{\circ}C$ , $f_{MCLK} = f_{(SMCLK)} = 1 \text{ MHz}$ ,	V <sub>CC</sub> = 2.2 V		200	250	^
I(AM)	Active mode	f(ACLK) = 32,768 Hz, Program executes in Flash	V <sub>CC</sub> = 3 V		300	350	μΑ
,		$T_A = -40^{\circ}C + 85^{\circ}C,$	V <sub>CC</sub> = 2.2 V		3	5	
		f(MCLK) = f(SMCLK) = f(ACLK) = 4096 Hz, Program executes in Flash	V <sub>CC</sub> = 3 V		11	18	μΑ
lesses	Low-power mode, (LPM0)	$T_A = -40^{\circ}\text{C} + 85^{\circ}\text{C},$	V <sub>CC</sub> = 2.2 V		32	45	^
I(CPUOff)	Low-power mode, (LPMO)	f(MCLK) = 0, $f(SMCLK) = 1$ MHz, f(ACLK) = 32,768 Hz	VCC = 3 V		55	70	μΑ
In many	Low-power mode, (LPM2)	$T_{A} = -40^{\circ}\text{C} + 85^{\circ}\text{C},$	V <sub>CC</sub> = 2.2 V		11	14	4
I(LPM2)		f(MCLK) = f(SMCLK) = 0 MHz, f(ACLK) = 32,768 Hz, SCG0 = 0	VCC = 3 V		17	22	μΑ
		$T_A = -40^{\circ}C$			0.8	1.2	μА
		T <sub>A</sub> = 25°C	V <sub>CC</sub> = 2.2 V		0.7	1	
I	Low nower made (LDM2)	T <sub>A</sub> = 85°C	]		1.6	2.3	
I(LPM3)	Low-power mode, (LPM3)	$T_A = -40^{\circ}C$			1.8	2.2	
		T <sub>A</sub> = 25°C	VCC = 3 V		1.6	1.9	μΑ
		T <sub>A</sub> = 85°C	]		2.3	3.4	
		$T_A = -40^{\circ}C$			0.1	0.5	
I(LPM4)	Low-power mode, (LPM4)	T <sub>A</sub> = 25°C	V <sub>CC</sub> = 2.2 V/3 V		0.1	).1 0.5 μ/	μΑ
•		T <sub>A</sub> = 85°C	]		0.8	1.9	

NOTES: 1. All inputs are tied to 0 V or V<sub>CC</sub>. Outputs do not source or sink any current.



# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

current consumption of active mode versus system frequency

 $I_{AM} = I_{AM[1 \text{ MHz}]} \times f_{system} [MHz]$ 

current consumption of active mode versus supply voltage

 $I_{AM} = I_{AM[3\ V]} + 120\ \mu A/V \times (V_{CC} - 3\ V)$ 

#### Schmitt-trigger inputs Port P1 to Port P3; P1.0 to P1.7, P2.0 to P2.5, P3.0 to P3.7

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
.,	Dec 20 consists as formed through a literature	V <sub>CC</sub> = 2.2 V	1.1	1.5	V
V <sub>IT+</sub>	Positive-going input threshold voltage	VCC = 3 V	1.5	1.9	]
V <sub>IT</sub> _ N	Al at a second of the first	V <sub>CC</sub> = 2.2 V	0.4	0.9	.,
	Negative-going input threshold voltage	V <sub>CC</sub> = 3 V	0.9	1.3	V
	Input voltage hyptogenia (V/	V <sub>CC</sub> = 2.2 V	0.3	1.1	V
V <sub>hys</sub>	Input voltage hysteresis, (V <sub>IT+</sub> - V <sub>IT-</sub> )	V <sub>CC</sub> = 3 V	0.5	1	]

# standard inputs - RST/NMI; TEST

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
$V_{IL}$	Low-level input voltage	V 22V/2V	VSS	V <sub>SS</sub> +0.6	V
٧ıH	High-level input voltage	V <sub>CC</sub> = 2.2 V / 3 V	0.8×V <sub>CC</sub>	Vcc	V

### inputs Px.x, TAx

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
			2.2 V/3 V	1.5			cycle
t(int)	External interrupt timing	Port P1, P2: P1.x to P2.x, External trigger signal for the interrupt flag, (see Note 1)	2.2 V	62			
	The interrupt rings, (eee ritate 1)	to the interrupt mag, (eee react)	3 V	50			ns
t(cap)	Times A continue timine	TAO TAA TAO	2.2 V	62			ns
	Timer_A, capture timing	TA0, TA1, TA2	3 V	50			ns
4	Timer_A clock frequency	TACLK INCLKATOR ATT	2.2 V			8	MHz
f(TAext)	externally applied to pin	TACLK, INCLK $t_{(H)} = t_{(L)}$	3 V			10	IVITZ
	Timer A clock fraguency	SMCL K or ACL K signal calcated	2.2 V			8	MU
f(TAint)	Timer_A clock frequency	SMCLK or ACLK signal selected	3 V			10	MHz

NOTES: 1. The external signal sets the interrupt flag every time the minimum  $t_{(int)}$  cycle and time parameters are met. It may be set even with trigger signals shorter than  $t_{(int)}$ . Both the cycle and timing specifications must be met to ensure the flag is set.  $t_{(int)}$  is measured in MCLK cycles.

#### leakage current

	PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
I <sub>lkg(Px.x)</sub>		Port P1: P1.x, $0 \le x \le 7$ (see Notes 1 and 2)	2.2 V/3 V			±50	•
	High-impedance leakage current	Port P2: P2.x, $0 \le x \le 5$ (see Notes 1 and 2)	2.2 V/3 V			±50	nA

NOTES: 1. The leakage current is measured with VSS or VCC applied to the corresponding pin(s), unless otherwise noted.

2. The leakage of the digital port pins is measured individually. The port pin must be selected for input and there must be no optional pullup or pulldown resistor.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

# outputs Port 1 to Port 3; P1.0 to P1.7, P2.0 to P2.5, P3.0 to P3.7

	PARAMETER	TEST	CONDITIONS		MIN	TYP MAX	UNIT
		$I_{(OHmax)} = -1.5 \text{ mA}$	V 00V	See Note 1	V <sub>CC</sub> -0.25	Vcc	
l.,	High lavel autout valence		VCC-0.6	Vcc	V		
VOH	High-level output voltage	$I_{(OHmax)} = -1.5 \text{ mA}$	V <sub>CC</sub> = 3 V	See Note 1	V <sub>CC</sub> -0.25	Vcc	V
		$I_{(OHmax)} = -6 \text{ mA}$		See Note 2	VCC-0.6	Vcc	
		$I_{(OLmax)} = 1.5 \text{ mA}$	V 00V	See Note 1	Vss	V <sub>SS</sub> +0.25	
1,,	Lavo laval autout valtana	I <sub>(OLmax)</sub> = 6 mA	$V_{CC} = 2.2 \text{ V}$	See Note 2	Vss	V <sub>SS</sub> +0.6	.,
VOL	Low-level output voltage	$I_{(OLmax)} = 1.5 \text{ mA}$	V 2.V	See Note 1	VSS	V <sub>SS</sub> +0.25	V
		I <sub>(OLmax)</sub> = 6 mA	VCC = 3 V	See Note 2	Vss	V <sub>SS</sub> +0.6	

- NOTES: 1. The maximum total current, I<sub>OHmax</sub> and I<sub>OLmax</sub>, for all outputs combined, should not exceed ±12 mA to hold the maximum voltage drop specified.
  - 2. The maximum total current, I<sub>OHmax</sub> and I<sub>OLmax</sub>, for all outputs combined, should not exceed ±48 mA to hold the maximum voltage drop specified.

#### outputs P1.x, P2.x, P3.x, TAx

F	PARAMETER	TEST	CONDITIONS	VCC	MIN	TYP	MAX	UNIT
f(P20)		P2.0/ACLK, $C_L = 20 \text{ pF}$ 2.2 V/3		2.2 V/3 V			fSystem	
f(TAx)	Output frequency	TA0, TA1, TA2, C <sub>L</sub> = 20 p Internal clock source, SM	0, TA1, TA2, C <sub>L</sub> = 20 pF, ernal clock source, SMCLK signal applied (see Note 1)		dc		fSystem	MHz
			fSMCLK = fLFXT1 = fXT1		40%		60%	
		P1.4/SMCLK, $C_L = 20 \text{ pF}$ $f_{SMCLK} = f_{LFXT1} = f_{LF}$ $f_{SMCLK} = f_{LFXT1/n}$	fSMCLK = fLFXT1 = fLF	2.2 V/3 V	35%		65%	
ĺ	Duty cycle of O/P frequency		fSMCLK = fLFXT1/n		50%- 15 ns	50%	50%+ 15 ns	
<sup>t</sup> (Xdc)		,	ſ	fSMCLK = fDCOCLK	2.2 V/3 V	50%– 15 ns	50%	50%+ 15 ns
			f <sub>P20</sub> = f <sub>LFXT1</sub> = f <sub>XT1</sub>		40%		60%	
		P2.0/ACLK, $C_L = 20 \text{ pF}$ $f_{P20} = f_{LFXT1} = f_{LF}$ $f_{P20} = f_{LFXT1/n}$	f <sub>P20</sub> = f <sub>LFXT1</sub> = f <sub>LF</sub>	2.2 V/3 V	30%		70%	
			f <sub>P20</sub> = f <sub>LFXT1/n</sub>			50%		
t(TAdc)		TA0, TA1, TA2,	C <sub>L</sub> = 20 pF, Duty cycle = 50%	2.2 V/3 V		0	±50	ns

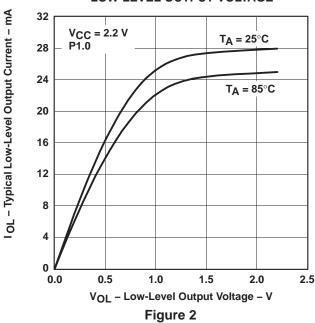
NOTES: 1. The limits of the system clock MCLK has to be met. MCLK and SMCLK can have different frequencies.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

outputs - Ports P1, P2, and P3 (see Note)

# TYPICAL LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE



# TYPICAL HIGH-LEVEL OUTPUT CURRENT vs

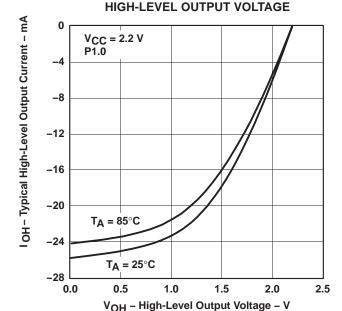
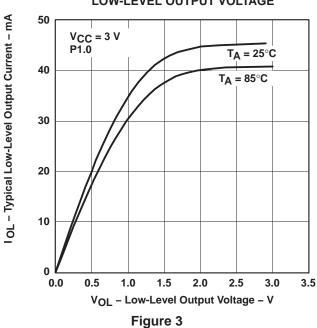


Figure 4

NOTE: Only one output is loaded at a time.

# TYPICAL LOW-LEVEL OUTPUT CURRENT vs LOW-LEVEL OUTPUT VOLTAGE



TYPICAL HIGH-LEVEL OUTPUT CURRENT

# HIGH-LEVEL OUTPUT VOLTAGE

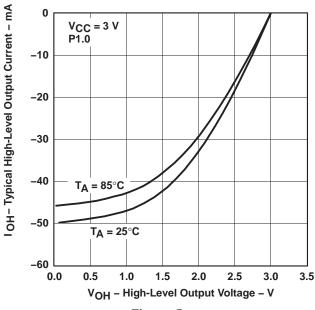


Figure 5



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

#### **USART** (see Note 1)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>(τ)</sub>	LICART: dealitab time	V <sub>CC</sub> = 2.2 V	200	430	800	no
	USART: deglitch time	V <sub>CC</sub> = 3 V	150	280	500	ns

NOTES: 1. The signal applied to the USART receive signal/terminal (URXD) should meet the timing requirements of t<sub>(τ)</sub> to ensure that the URXS flip-flop is set. The URXS flip-flop is set with negative pulses meeting the minimum-timing condition of t<sub>(τ)</sub>. The operating conditions to set the flag must be met independently from this timing constraint. The deglitch circuitry is active only on negative transitions on the URXD line.

#### **RAM**

	PARAMETER	MIN	NOM	MAX	UNIT
V(RAMh)	CPU halted (see Note 1)	1.6			V

NOTES: 1. This parameter defines the minimum supply voltage V<sub>CC</sub> when the data in the program memory RAM remains unchanged. No program execution should happen during this supply voltage condition.

#### POR brownout, reset (see Notes 1 and 2)

PARAMI	ETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
td(BOR)					2000	μs
V <sub>CC(start)</sub>		$dV_{CC}/dt \le 3 V/s$	0.	$7 \times V_{(B\_IT)}$	<b>-</b> )	٧
V(B_IT-)	Brownout	$dV_{CC}/dt \le 3 V/s$			1.71	V
V <sub>hys(B_IT-)</sub>		$dV_{CC}/dt \le 3 V/s$	70	130	180	mV
t(reset)		Pulse length needed at $\overline{RST}/NMI$ pin to accepted reset internally, $V_{CC} = 2.2 \text{ V/3 V}$	2			μs

NOTES: 1. The current consumption of the brown-out module is already included in the I<sub>CC</sub> current consumption data.

During power up, the CPU begins code execution following a period of t<sub>d</sub>(BOR) after V<sub>CC</sub> = V<sub>(B\_IT-)</sub> + V<sub>hys</sub>(B\_IT-).
 The default DCO settings must not be changed until V<sub>CC</sub> ≥ V<sub>CC(min)</sub>. See the MSP430x1xx Family User's Guide for more information on the brownout circuit.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

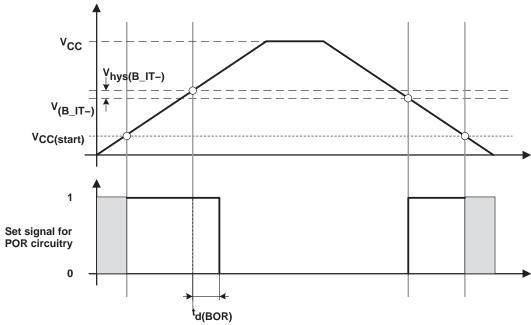


Figure 6. POR/Brownout Reset (BOR) vs Supply Voltage

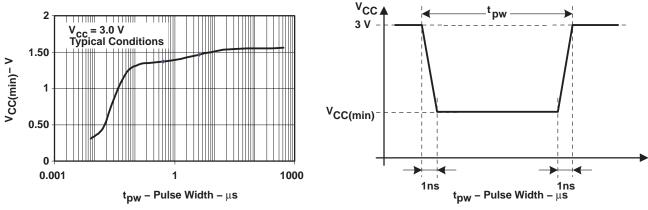


Figure 7. V<sub>CC(min)</sub> Level With a Square Voltage Drop to Generate a POR/Brownout Signal

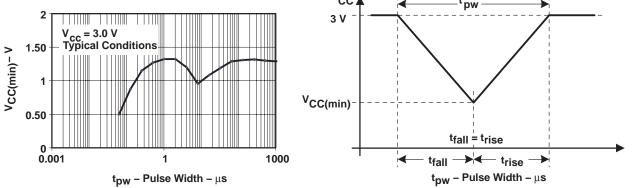


Figure 8. V<sub>CC(min)</sub> Level With a Triangle Voltage Drop to Generate a POR/Brownout Signal



# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

# crystal oscillator,LFXT1

P	ARAMETER	TEST CONDITIONS	VCC	MIN	TYP MAX	UNIT
	Pin load	XTS=0; LF mode selected	2.2 V / 3 V		12	1
C <sub>XIN</sub>	capacitance	XTS=1; XT1 mode selected (see Note 1) 2.2 V / 3 V 2		2	pF	
0	Pin load	XTS=0; LF mode selected	2.2 V / 3 V	12		
Схоит	capacitance	XTS=1; XT1 mode selected (see Note 1)	2.2 V / 3 V		2	pF
V <sub>IL</sub>	Input levels at XIN	see Note 2	2.2 V / 3 V	VSS	0.2 × V <sub>CC</sub>	V
$V_{\text{IH}}$	input levels at Ally	SEC INDIC 2	Z.Z V / 3 V	$0.8 \times V_{CC}$	Vcc	V

NOTES: 1. Requires external capacitors at both terminals. Values are specified by crystal manufacturers.

2. Applies only when using an external logic-level clock source. Not applicable when using a crystal or resonator.

#### **DCO**

PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	UNIT
f	B . 0 DCO 2 MOD 0 DCOD 0 T. 050C	2.2 V	0.08	0.12	0.15	NAL I-
f(DCO03)	$R_{Sel} = 0$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	3 V	0.08	0.13	0.16	MHz
f(DOO(s)	$R_{Sel} = 1$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	2.2 V	0.14	0.19	0.23	MHz
f(DCO13)	N <sub>Sel</sub> = 1, DCO = 3, WOD = 0, DCON = 0, 1A = 23 C	3 V	0.14	0.18	0.22	IVII IZ
f(DCO23)	$R_{Sel} = 2$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	2.2 V	0.22	0.3	0.36	MHz
·(DCO23)	NSel = 2, 200 = 0, MOD = 0, 200 N = 0, 1A = 20 0	3 V	0.22	0.28	0.34	1411.12
f(DOORS)	$R_{Sel} = 3$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	2.2 V	0.37	0.49	0.59	MHz
f(DCO33)	Nge  = 3, Boo = 3, Mob = 0, Book = 0, 1A = 23 0	3 V	0.37	0.47	0.56	IVII IZ
f(DOO (0)	$R_{Sel} = 4$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	2.2 V	0.61	0.77	0.93	MHz
f(DCO43)	N <sub>Sel</sub> = 4, DCO = 3, NOD = 0, DCON = 0, 1A = 23 C	3 V	0.61	0.75	0.9	IVII IZ
fraces	$R_{Sel} = 5$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	2.2 V	1	1.2	1.5	MHz
f(DCO53)	N <sub>Sel</sub> = 5, DOO = 5, MOD = 0, DOOK = 0, 1 <sub>A</sub> = 25 C	3 V	1	1.3	1.5	IVII IZ
<i>t</i> = 2 = 2	$R_{Sel} = 6$ , DCO = 3, MOD = 0, DCOR = 0, $T_A = 25$ °C	2.2 V	1.6	1.9	2.2	MHz
f(DCO63)	$ R_{Sel}=0$ , $DCO=3$ , $ MOD=0$ , $DCOR=0$ , $ I_A=23 C$	3 V	1.69	2	2.29	IVITIZ
<b>4</b>	R <sub>Sel</sub> = 7, DCO = 3, MOD = 0, DCOR = 0, T <sub>A</sub> = 25°C	2.2 V	2.4	2.9	3.4	MHz
f(DCO73)	$ R_{Sel}=7, DCO=3, MOD=0, DCOR=0,  IA=23 C$	3 V	2.7	3.2	3.65	IVITIZ
,	D 7 D00 7 M0D 0 D00D 0 7 0500	2.2 V	4	4.5	4.9	
f(DCO77)	$R_{Sel} = 7$ , DCO = 7, MOD = 0, DCOR = 0, $T_A = 25$ °C	3 V	4.4	4.9	5.4	MHz
f(DCO47)	R <sub>Sel</sub> = 4, DCO = 7, MOD = 0, DCOR = 0, T <sub>A</sub> = 25°C	2.2 V/3 V	fDCO40	fDCO40	fDCO40	MHz
	7.		x1.7	x2.1	x2.5	
S <sub>(Rsel)</sub>	S <sub>R</sub> = f <sub>Rsel+1</sub> /f <sub>Rsel</sub>	2.2 V/3 V	1.35	1.65	2	ratio
S <sub>(DCO)</sub>	$S_{DCO} = f_{DCO+1}/f_{DCO}$	2.2 V/3 V	1.07	1.12	1.16	
D.	Temperature drift, R <sub>Sel</sub> = 4, DCO = 3, MOD = 0 (see Note 1)	2.2 V	-0.31	-0.36	-0.4	%/°C
Dt	Temperature unit, NSE  = 4, DOO = 3, INIOD = 0 (See Note 1)	3 V	-0.33	-0.38	-0.43	70/ C
DV	Drift with V <sub>CC</sub> variation, R <sub>Sel</sub> = 4, DCO = 3, MOD = 0 (see Note 1)	2.2 V/3 V			±5	%/V

NOTES: 1. These parameters are not production tested.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

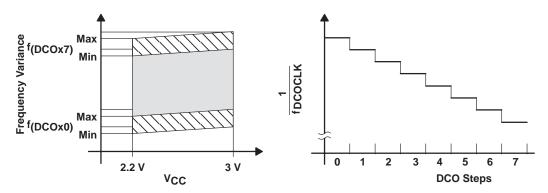


Figure 9. DCO Characteristics

#### principle characteristics of the DCO

- Individual devices have a minimum and maximum operation frequency. The specified parameters for f<sub>DCOx0</sub> to f<sub>DCOx7</sub> are valid for all devices.
- The DCO control bits DCO0, DCO1 and DCO2 have a step size as defined in parameter S<sub>DCO</sub>.
- The modulation control bits MOD0 to MOD4 select how often  $f_{DCO+1}$  is used within the period of 32 DCOCLK cycles.  $f_{DCO}$  is used for the remaining cycles. The frequency is an average =  $f_{DCO} \times (2^{MOD/32})$ .
- All ranges selected by R<sub>sel(n)</sub> overlap with R<sub>sel(n+1)</sub>: R<sub>sel0</sub> overlaps with R<sub>sel1</sub>, ... R<sub>sel6</sub> overlaps with R<sub>sel7</sub>.

### wake-up from lower power modes (LPMx)

	PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
t(LPM0)		V <sub>CC</sub> = 2.2 V/3 V			100		
t(LPM2)		V <sub>CC</sub> = 2.2 V/3 V			100		ns
		f(MCLK) = 1 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	
t(LPM3)	Delevitime (and Nate 4)	f(MCLK) = 2 MHz,	V <sub>CC</sub> = 2.2 V/3 V			6	μs
	Delay time (see Note 1)	f(MCLK) = 3 MHz,	$V_{CC} = 2.2 \text{ V/3 V}$			6	
		$f_{(MCLK)} = 1 MHz,$	$V_{CC} = 2.2 \text{ V/3 V}$			6	
<sup>t</sup> (LPM4)		$f_{(MCLK)} = 2 MHz,$	$V_{CC} = 2.2 \text{ V/3 V}$			6	μs
		f(MCLK) = 3 MHz,	$V_{CC} = 2.2 \text{ V/3 V}$			6	

NOTES: 1. Parameter applicable only if DCOCLK is used for MCLK.



# electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

#### 10-bit ADC, power supply and input range conditions (see Note 1)

	PARAMETER	TEST CONDITIONS	3	MIN	NOM	MAX	UNIT
VCC	Analog supply voltage	V <sub>SS</sub> = 0 V		2.2		3.6	V
V(P6.x/Ax)	Analog input voltage range (see Note 2)	All Ax terminals. Analog inputs selected in ADC10AE register and P. VSS ≤ VPx.x/Ax ≤ VCC	elected in ADC10AE register and PxSel.x=1			VCC	V
1	Operating supply current	fADC10CLK = 5.0 MHz ADC10ON = 1, REFON = 0	2.2 V		0.52	1.05	A
IADC10	into V <sub>C</sub> C terminal (see Note 3)	ADC10SHT0=1, ADC10SHT1=0, ADC10DIV=0	3 V		0.6	1.2	mA
IREF+	Reference operating supply current, reference buffer disabled (see Note 4)	fADC10CLK = 5.0 MHz ADC10ON = 0, REFON = 1, REF2_5V = x; REFOUT = 0	2.2V/3 V		0.25	0.4	mA
1	Reference buffer operating supply current	fADC10CLK = 5.0 MHz ADC10ON = 0,	ADC10SR = 0		1.1	1.4	mA
<sup>I</sup> REFB	(see Note 4)	REFON = 1, REF2_5V = 0 REFOUT = 1	ADC10SR = 1		0.46	0.55	MA
C <sub>I</sub> †	Input capacitance	Only one terminal can be selected at one time, Px.x/Ax	2.2 V			27	pF
R <sub>I</sub> †	Input MUX ON resistance	$0V \le V_{AX} \le V_{CC}$	3 V			2000	Ω

<sup>†</sup> Not production tested, limits verified by design

NOTES: 1. The leakage current is defined in the leakage current table with Px.x/Ax parameter.

- 2. The analog input voltage range must be within the selected reference voltage range  $V_{R+}$  to  $V_{R-}$  for valid conversion results.
- 3. The internal reference supply current is not included in current consumption parameter I<sub>ADC10</sub>.
- 4. The internal reference current is supplied via terminal V<sub>CC</sub>. Consumption is independent of the ADC10ON control bit, unless a conversion is active. The REFON bit enables the built-in reference to settle before starting an A/D conversion.

#### 10-bit ADC, external reference (see Note 1)

PA	RAMETER	TEST CONDITIONS		MIN	NOM	MAX	UNIT
V <sub>eREF+</sub>	Positive external reference voltage input	V <sub>eREF+</sub> > V <sub>REF</sub> _/V <sub>eREF</sub> _ (see Note 2)	/eREF+ > VREF_/VeREF_ (see Note 2)			VCC	V
VREF-/VeREF-	Negative external reference voltage input	VeREF+ > VREF_/VeREF_ (see Note 3)		0		1.2	V
(V <sub>eREF+</sub> - V <sub>REF-/</sub> V <sub>eREF-</sub> )	Differential external reference voltage input	V <sub>eREF+</sub> > V <sub>REF-</sub> /V <sub>eREF-</sub> (see Note 4)		1.4		VCC	V
I <sub>VeREF+</sub>	Static input current	0V ≤VeREF+ ≤ VCC	2.2 V/3 V			±1	μΑ
IVREF-/VeREF-	Static input current	0V ≤ V <sub>eREF</sub> – ≤ V <sub>CC</sub>	2.2 V/3 V			±1	μΑ

- NOTES: 1. The external reference is used during conversion to charge and discharge the capacitance array. The input capacitance, C<sub>1</sub>, is also the dynamic load for an external reference during conversion. The dynamic impedance of the reference supply should follow the recommendations on analog-source impedance to allow the charge to settle for 10-bit accuracy.
  - 2. The accuracy limits the minimum positive external reference voltage. Lower reference voltage levels may be applied with reduced accuracy requirements.
  - 3. The accuracy limits the maximum negative external reference voltage. Higher reference voltage levels may be applied with reduced accuracy requirements.
  - 4. The accuracy limits minimum external differential reference voltage. Lower differential reference voltage levels may be applied with reduced accuracy requirements.



# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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# electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

# 10-bit ADC, built-in reference

Р	ARAMETER	TEST CONDITIONS	;	MIN	NOM	MAX	UNIT
	Positive built-in reference	REF2_5V = 1 for 2.5 V $ VREF+ \le  VREF+max $	3 V	2.35	2.5	2.65	
VREF+	voltage output	REF2_5V = 0 for 1.5 V $ VREF+ \le  VREF+max $	2.2 V/3 V	1.41	1.5	1.59	V
	V <sub>CC</sub> minimum voltage,	REF2_5V = 0, $I_{VREF+} \le 1 \text{mA}$	•	2.2			
VCC(min)	Positive built-in reference	REF2_5V = 1, $I_{VREF+} \le 0.5 \text{mA}$		V <sub>REF+</sub> +	0.15		V
, ,	active	REF2_5V = 1, $I_{VREF+} \le 1mA$		V <sub>REF+</sub> +	0.15		
h	Load current out of VREF+		2.2 V			±0.5	mA
I <sub>VREF+</sub>	terminal		3 V			±1	mA
		IVREF+ = 500 μA +/– 100 μA Analog input voltage ~0.75 V;	2.2 V			±2	LSB
· +	Load-current regulation	REF2_5V = 0	3 V			±2	LOD
IL(VREF)+ †	V <sub>REF+</sub> terminal	IVREF+ = 500 μA $\pm$ 100 μA Analog input voltage ~1.25 V; REF2_5V = 1	3 V			±2	LSB
. +	Load current regulation	I <sub>VREF+</sub> =100 μA → 900 μA,	ADC10SR = 0			400	
<sup>t</sup> DL(VREF) + <sup>‡</sup>	V <sub>REF+</sub> terminal	V <sub>CC</sub> =3 V, Ax ~0.5 x V <sub>REF+</sub> Error of conversion result ≤ 1 LSB	ADC10SR = 1			2000	ns
C <sub>VREF+</sub>	Capacitance at pin V <sub>REF+</sub> (see Note 1)	REFON =1, I <sub>VREF+</sub> ≤±1 mA	2.2 V/3 V			100	pF
T <sub>REF+</sub> †	Temperature coefficient of built-in reference	I <sub>VREF+</sub> is a constant in the range of 0 mA ≤ I <sub>VREF+</sub> ≤ 1 mA	2.2 V/3 V			±100	ppm/°C
Settle time of internal reference voltage and		$I_{VREF+} = 0.5 \text{ mA}, V_{REF+} = 1.5 \text{ V}, V_{CC} = 3.6 \text{ V},$ REFON = $0 \rightarrow 1$				30	
tREFON <sup>†</sup>	VREF+	$I_{VREF+} = 0.5 \text{ mA}, V_{REF+} = 1.5 \text{ V},$	ADC10SR = 0			0.8	μs
	(see Note 2)	V <sub>CC</sub> = 2.2 V, REFON = 1	ADC10SR = 1			2.5	

<sup>†</sup> Not production tested, limits characterized

NOTES: 2. The condition is that the error in a conversion started after  $t_{REFON}$  is less than  $\pm 0.5$  LSB.



<sup>‡</sup> Not production tested, limits verified by design

NOTES: 1. The capacitance applied to the internal buffer operational amplifier, if switched to terminal P2.4/TA2/A4/V<sub>REF+</sub>/V<sub>eREF+</sub> (REFOUT=1), must be limited; the reference buffer may become unstable otherwise.

# electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

#### 10-bit ADC, timing parameters

Р	ARAMETER	TEST CONDITION	S	MIN	NOM	MAX	UNIT
,		Error of conversion result ≤ ±1	ADC10SR = 0	0.450		6.3	
fADC10CLK		LSB	ADC10SR = 1	0.450		1.5	MHz
fADC10OSC		ADC10DIV=0, fADC10CLK=fADC10OSC	2.2 V/ 3V	3.7		6.3	MHz
†CONVERT	Conversion time	Internal oscillator, fADC10OSC = 3.7 MHz to 6.3 MHz	2.2 V/ 3 V	2.06		3.51	μs
OONVERN		External fADC10CLK from ACLK, MCLK or SMCLK: ADC10SSEL ≠ 0			13×ADC10DIV× 1/fADC10CLK		μs
tADC100N <sup>‡</sup>	Turn on settling time of the ADC	(see Note 1)				100	ns
to . †	Sampling time	$R_S = 400 \Omega$ , $R_I = 2000 \Omega$ ,	3 V	1400			20
<sup>t</sup> Sample <sup>‡</sup>	Sampling wife	C <sub>I</sub> = 20 pF (see Note 2)	2.2 V	1400		·	ns

<sup>&</sup>lt;sup>†</sup> Not production tested, limits characterized

NOTES: 1. The condition is that the error in a conversion started after t<sub>ADC10ON</sub> is less than ±0.5 LSB. The reference and input signal are already settled.

2. Approximately eight Tau  $(\tau)$  are needed to get an error of less than  $\pm 0.5$  LSB.  $t_{Sample} = ln(2^{n+1}) \times (R_S + R_I) \times C_I + 800 \text{ ns.}$  (ADC10SR = 0, n = ADC resolution = 10,  $R_S$  = external source resistance)  $t_{Sample} = ln(2^{n+1}) \times (R_S + R_I) \times C_I + 2.5 \,\mu s.$  (ADC10SR = 1, n = ADC resolution = 10,  $R_S$  = external source resistance)

# 10-bit ADC, linearity parameters

	PARAMETER	TEST CONDITIONS		MIN	NOM	MAX	UNIT
_	late and linearity amon	$1.4 \text{ V} \le (V_{eREF+} - V_{REF-}/V_{eREF-}) \text{ min} \le 1.6 \text{ V}$	0.0.1/0.1/			±1	1.00
Εl	Integral linearity error	$1.6 \text{ V} < (\text{V}_{\text{eREF+}} - \text{V}_{\text{REF-}}/\text{V}_{\text{eREF-}}) \text{ min } \leq [\text{V}_{\text{CC}}]$	2.2 V/3 V			±1	LSB
E <sub>D</sub>	Differential linearity error	(VeREF+-VREF_VeREF-)min≤(VeREF+-VREF_VeREF-)	2.2 V/3 V			±1	LSB
EO	Offset error	(VeREF+ – VREF_/VeREF_)min $\leq$ (VeREF+ – VREF_/VeREF_), Internal impedance of source RS < 100 $\Omega,$	2.2 V/3 V		±2	±4	LSB
EG	Gain error	$(V_{eREF+} - V_{REF-})_{min} \le (V_{eREF+} - V_{REF-})_{eREF-})_{ereF}$	2.2 V/3 V		±1.1	±2	LSB
ET	Total unadjusted error	$(V_{eREF+} - V_{REF-})_{min} \le (V_{eREF+} - V_{REF-})_{eREF-}),$	2.2 V/3 V		±2	±5	LSB

<sup>‡</sup> Not production tested, limits verified by design

# MSP430x11x2, MSP430x12x2 MIXED SIGNAL MICROCONTROLLER

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# electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

# 10-bit ADC, temperature sensor and built-in V<sub>MID</sub>

	PARAMETER	TEST CONDITIONS		MIN	NOM	MAX	UNIT		
	Operating supply current into	REFON = 0, INCH = 0Ah,	2.2 V		40	120			
ISENSOR	V <sub>CC</sub> terminal (see Note 1)	ADC10ON=NA, T <sub>A</sub> = 25°C	3 V		60	160	μΑ		
·/ +		ADC10ON = 1, INCH = 0Ah,	2.2 V		986	986±5%	>/		
VSENSOR <sup>†</sup>		$T_A = 0$ °C	3 V		986	986±5%	mV		
TO +		ADC10ON = 1, INCH = 0Ah $\frac{2.2}{3 \text{ V}}$			3.55	3.55±3%			
TC <sub>SENSOR</sub> †					3.55	3.55±3%	mV/°C		
	Sample time required if channel	ADC10ON = 1, INCH = 0Ah,	2.2 V	30			_		
<sup>t</sup> SENSOR(sample) <sup>†</sup>	10 is selected (see Note 2)	Error of conversion result ≤ 1 LSB	3 V	30			μs		
	Current into divider at channel 11	ADOLOGNI A INICII ODI	2.2 V			NA			
IVMID	(see Note 3)	ADC100N = 1, INCH = 0Bh,	3 V			NA	μΑ		
Maria	Manadadan at abanasa 44	ADC10ON = 1, INCH = 0Bh,	2.2 V		1.1	1.1±0.04	V		
VMID	V <sub>CC</sub> divider at channel 11	V <sub>MID</sub> is ~0.5 x V <sub>CC</sub> 3 V			1.5	1.50±0.04	V		
<b>.</b>	Sample time required if channel	ADC10ON = 1, INCH = 0Bh, 2.3		el ADC100N = 1, INCH = 0Bh, 2.2 V 1400		1400			200
tVMID(sample)	11 is selected (see Note 4)	Error of conversion result ≤ 1 LSB	3 V	1220			ns		

<sup>†</sup> Not production tested, limits characterized

NOTES: 1. The sensor current I<sub>SENSOR</sub> is consumed if (ADC10ON = 1 and REFON = 1), or (ADC10ON=1 and INCH=0Ah and sample signal is high). Therefore it includes the constant current through the sensor and the reference.

- 2. The typical equivalent impedance of the sensor is 51 k $\Omega$ . The sample time required includes the sensor-on time tSENSOR(on).
- 3. No additional current is needed. The  $\mbox{\ensuremath{V_{\mbox{\footnotesize MID}}}}$  is used during sampling.
- 4. The on-time tymino(on) is included in the sampling time tymino(sample); no additional on time is needed.



# electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

#### Flash Memory

	PARAMETER	TEST CONDITIONS	VCC	MIN	NOM	MAX	UNIT
VCC(PGM/ ERASE)	Program and Erase supply voltage			2.7		3.6	٧
fFTG	Flash Timing Generator frequency			257		476	kHz
IPGM	Supply current from V <sub>CC</sub> during program		2.7 V/ 3.6 V		3	5	mA
IERASE	Supply current from V <sub>CC</sub> during erase		2.7 V/ 3.6 V		3	7	mA
tCPT	Cumulative program time	see Note 1	2.7 V/ 3.6 V			4	ms
tCMErase	Cumulative mass erase time	see Note 2	2.7 V/ 3.6 V	200			ms
	Program/Erase endurance			10 <sup>4</sup>	10 <sup>5</sup>		cycles
<sup>t</sup> Retention	Data retention duration	T <sub>J</sub> = 25°C		100			years
<sup>t</sup> Word	Word or byte program time				35		
<sup>t</sup> Block, 0	Block program time for 1 <sup>St</sup> byte or word				30		
<sup>t</sup> Block, 1-63	Block program time for each additional byte or word	N 2			21		4
<sup>t</sup> Block, End	Block program end-sequence wait time	see Note 3			6		tFTG
<sup>t</sup> Mass Erase	Mass erase time				5297		
tSeg Erase	Segment erase time				4819		

- NOTES: 1. The cumulative program time must not be exceeded during a block-write operation. This parameter is only relevant if the block write feature is used.
  - 2. The mass erase duration generated by the flash timing generator is at least 11.1ms (= 5297x1/f<sub>FTG</sub>,max = 5297x1/476kHz). To achieve the required cumulative mass erase time the Flash Controller's mass erase operation can be repeated until this time is met. (A worst case minimum of 19 cycles are required).
  - 3. These values are hardwired into the Flash Controller's state machine;  $t_{FTG} = 1/f_{FTG}$ .

#### **JTAG Interface**

	PARAMETER	TEST CONDITIONS	Vcc	MIN	NOM	MAX	UNIT
,	TOW is not for more and	and Mate 4	2.2 V	0		5	MHz
f <sub>TCK</sub> TCK input frequency		see Note 1	3 V	0		10	MHz
R <sub>Internal</sub>	Internal pull-up resistance on TMS, TCK, TDI/TCLK	see Note 2	2.2 V/ 3 V	25	60	90	kΩ

NOTES: 1. f<sub>TCK</sub> may be restricted to meet the timing requirements of the module selected.

2. TMS, TDI/TCLK, and TCK pull-up resistors are implemented in all Flash versions.

#### JTAG Fuse (see Note 1)

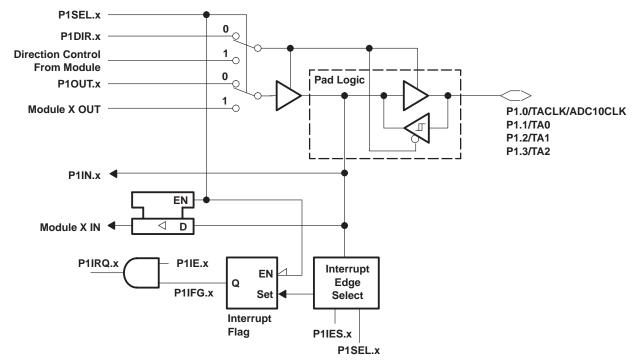
	PARAMETER	TEST CONDITIONS	VCC	MIN	NOM	MAX	UNIT
V <sub>CC(FB)</sub>	Supply voltage during fuse-blow condition	T <sub>A</sub> = 25°C		2.5			V
$V_{FB}$	Voltage level on TEST for fuse-blow			6		7	V
I <sub>FB</sub>	Supply current into TEST during fuse blow					100	mA
tFB	Time to blow fuse					1	ms

NOTES: 1. Once the fuse is blown, no further access to the MSP430 JTAG/Test and emulation features is possible. The JTAG block is switched to bypass mode.



# input/output schematic

# Port P1, P1.0 to P1.3, input/output with Schmitt-trigger



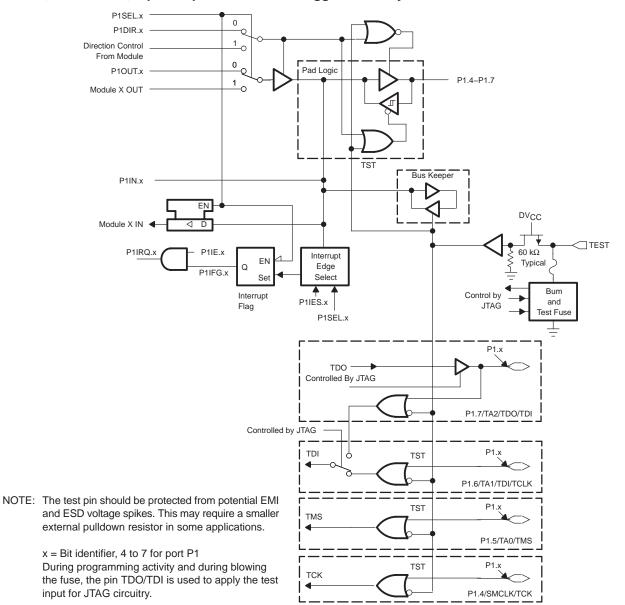
NOTE: x = Bit/identifier, 0 to 3 for port P1

PnSel.x	PnDIR.x	DIRECTION CONTROL FROM MODULE	PnOUT.x	MODULE X OUT	PnIN.x	MODULE X IN	PnIE.x	PnIFG.x	PnIES.x
P1Sel.0	P1DIR.0	P1DIR.0	P1OUT.0	ADC10CLK	P1IN.0	TACLK <sup>†</sup>	P1IE.0	P1IFG.0	P1IES.0
P1Sel.1	P1DIR.1	P1DIR.1	P1OUT.1	Out0 signal†	P1IN.1	CCI0A†	P1IE.1	P1IFG.1	P1IES.1
P1Sel.2	P1DIR.2	P1DIR.2	P1OUT.2	Out1 signal <sup>†</sup>	P1IN.2	CCI1A <sup>†</sup>	P1IE.2	P1IFG.2	P1IES.2
P1Sel.3	P1DIR.3	P1DIR.3	P1OUT.3	Out2 signal <sup>†</sup>	P1IN.3	CCI2A†	P1IE.3	P1IFG.3	P1IES.3

<sup>†</sup> Signal from or to Timer\_A

# input/output schematic (continued)

# Port P1, P1.4 to P1.7, input/output with Schmitt-trigger and in-system access features



PnSel.x	PnDIR.x	DIRECTION CONTROL FROM MODULE	PnOUT.x	MODULE X OUT	PnIN.x	MODULE X IN	PnIE.x	PnIFG.x	PnIES.x
P1Sel.4	P1DIR.4	P1DIR.4	P1OUT.4	SMCLK	P1IN.4	unused	P1IE.4	P1IFG.4	P1IES.4
P1Sel.5	P1DIR.5	P1DIR.5	P1OUT.5	Out0 signal†	P1IN.5	unused	P1IE.5	P1IFG.5	P1IES.5
P1Sel.6	P1DIR.6	P1DIR.6	P1OUT.6	Out1 signal <sup>†</sup>	P1IN.6	unused	P1IE.6	P1IFG.6	P1IES.6

Out2 signal†

P1DIR.7

P1DIR.7

P1OUT.7



P1IN.7

unused

P1IE.7

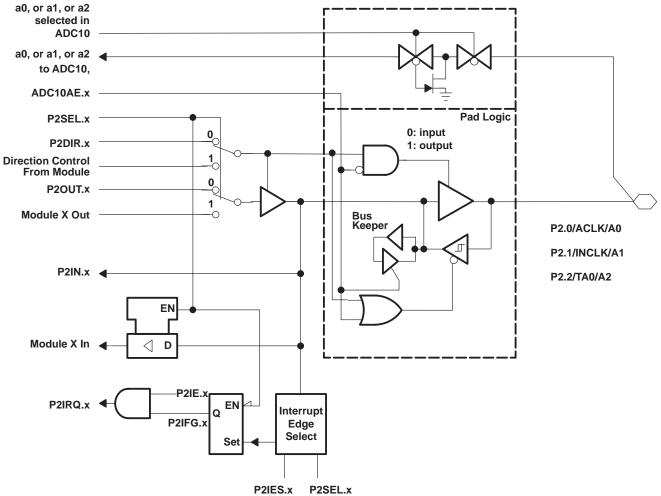
P1IFG.7

P1IES.7

<sup>†</sup> Signal from or to Timer\_A

# input/output schematic (continued)

# Port P2, P2.0 to P2.2, input/output with Schmitt-trigger



NOTE:  $0 \le x \le 2$ 

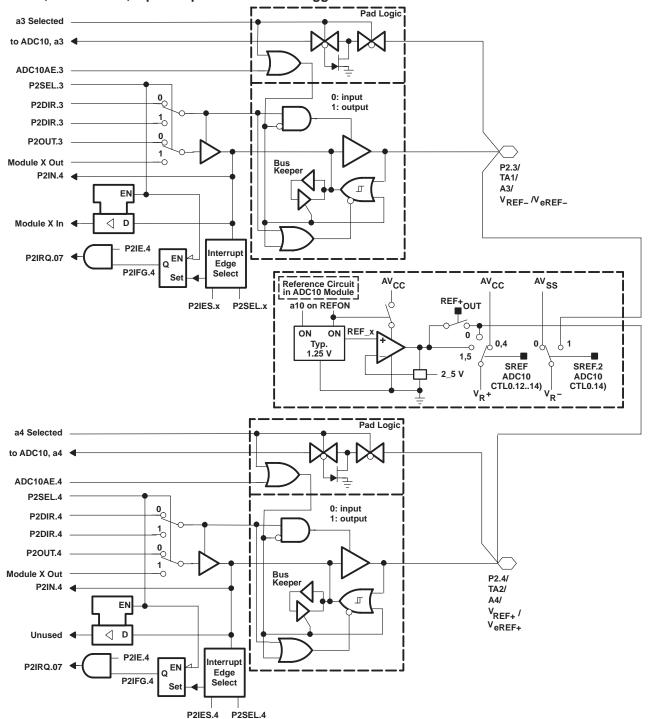
PnSel.x	PnDIR.x	DIRECTION CONTROL FROM MODULE	PnOUT.x	MODULE X OUT	PnIN.x	MODULE X IN	PnIE.x	PnIFG.x	PnlES.x
P2Sel.0	P2DIR.0	P2DIR.0	P2OUT.0	ACLK <sup>†</sup>	P2IN.0	unused	P2IE.0	P2IFG.0	P1IES.0
P2Sel.1	P2DIR.1	P2DIR.1	P2OUT.1	V <sub>SS</sub>	P2IN.1	INCLK <sup>†</sup>	P2IE.1	P2IFG.1	P1IES.1
P2Sel.2	P2DIR.2	P2DIR.2	P2OUT.2	OUT0 signal <sup>†</sup>	P2IN.2	CCI0B <sup>†</sup>	P2IE.2	P2IFG.2	P1IES.2

† Timer\_A



# input/output schematic (continued)

# Port P2, P2.3 to P2.4, input/output with Schmitt-trigger



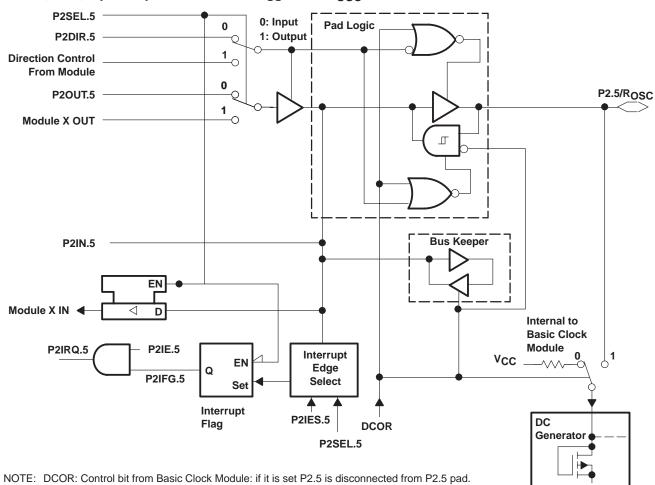
#### Port P2, P2.3 to P2.4, input/output with Schmitt-trigger (continued)

PnSel.x	PnDIR.x	DIRECTION CONTROL FROM MODULE	PnOUT.x	MODULE X OUT	PnIN.x	MODULE X IN	PnIE.x	PnIFG.x	PnlES.x
P2Sel.3	P2DIR.3	P2DIR.3	P2OUT.3	Out1 signal <sup>†</sup>	P2IN.3	CCI1B <sup>†</sup>	P2IE.3	P2IFG.3	P1IES.3
P2Sel.4	P2DIR.4	P2DIR.4	P2OUT.4	Out2 signal†	P2IN.4	Unused	P2IE.4	P2IFG.4	P1IES.4

<sup>†</sup> Timer A

# input/output schematic (continued)

# Port P2, P2.5, input/output with Schmitt-trigger and ROSC function for the Basic Clock Module

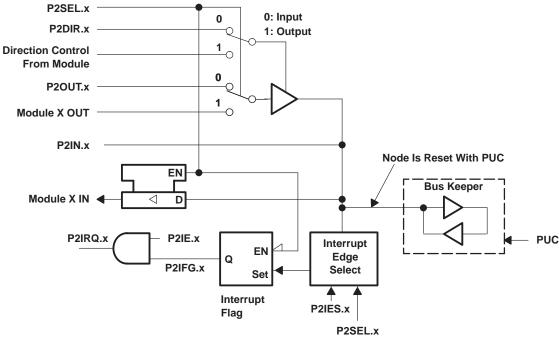


PnSel.x	PnDIR.x	DIRECTION CONTROL FROM MODULE		MODULE X OUT	PnIN.x	MODULE X IN	PnIE.x	PnIFG.x	PnIES.x
P2Sel.5	P2DIR.5	P2DIR.5	P2OUT.5	$V_{SS}$	P2IN.5	unused	P2IE.5	P2IFG.5	P2IES.5



# input/output schematic (continued)

# Port P2, unbonded bits P2.6 and P2.7



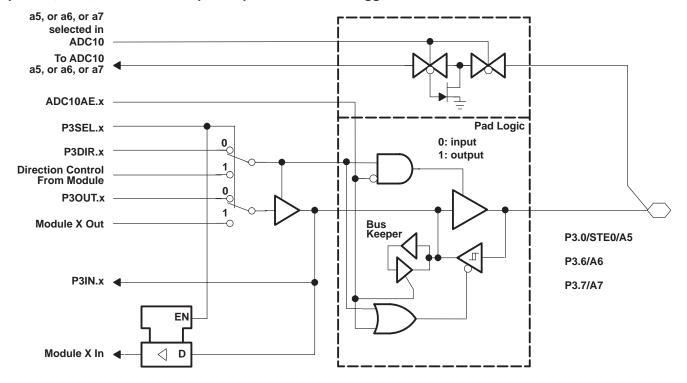
NOTE: x = Bit/identifier, 6 to 7 for port P2 without external pins

P2Sel.x	P2DIR.x	DIRECTION CONTROL FROM MODULE		MODULE X OUT	P2IN.x	MODULE X IN	P2IE.x	P2IFG.x	P2IES.x
P2Sel.6	P2DIR.6	P2DIR.6	P2OUT.6	V <sub>SS</sub>	P2IN.6	unused	P2IE.6	P2IFG.6	P2IES.6
P2Sel.7	P2DIR.7	P2DIR.7	P2OUT.7	V <sub>SS</sub>	P2IN.7	unused	P2IE.7	P2IFG.7	P2IES.7

NOTE: Unbonded bits 6 and 7 of port P2 can be used as interrupt flags. Only software can affect the interrupt flags. They work as software interrupts.

# input/output schematic (continued)

# port P3, P3.0, P3.6 and P3.7 input/output with Schmitt-trigger



NOTE: x (0,6,7)

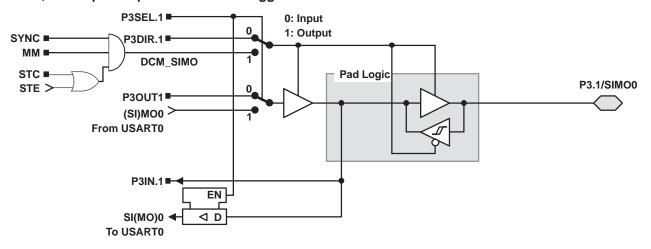
PnSel.x	PnDIR.x	Direction Control From Module	PnOUT.x	Module X OUT	PnIN.x	Module X IN
P3Sel.0	P3DIR.0	V <sub>SS</sub>	P3OUT.0	V <sub>SS</sub>	P3IN.0	STE0†
P3Sel.6	P3DIR.1	P3DIR.6	P3OUT.6	V <sub>SS</sub>	P3IN.6	Unused
P3Sel.7	P3DIR.2	P3DIR.7	P3OUT.7	V <sub>SS</sub>	P3IN.7	Unused

†USART0

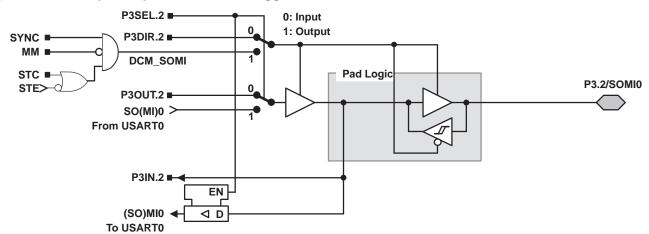


# input/output schematic (continued)

# port P3, P3.1 input/output with Schmitt-trigger

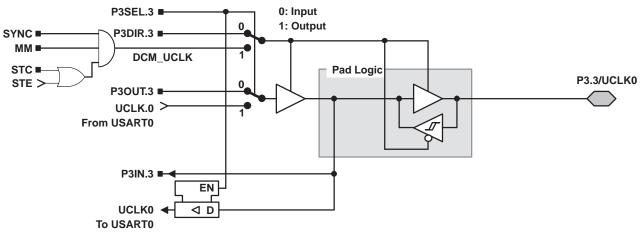


# port P3, P3.2, input/output with Schmitt-trigger



# input/output schematic (continued)

# port P3, P3.3, input/output with Schmitt-trigger

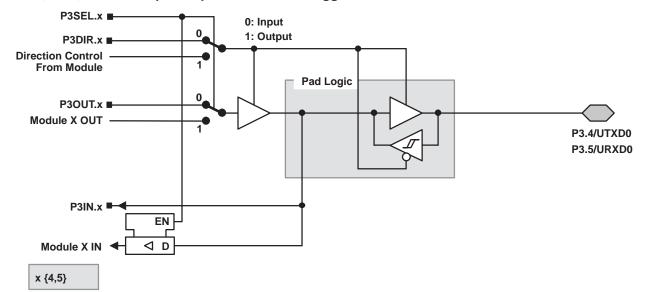


NOTE: UART mode: The UART clock can only be an input. If UART mode and UART function are selected, the P3.3/UCLK0 is always

SPI, slave mode: The clock applied to UCLK0 is used to shift data in and out.

SPI, master mode: The clock to shift data in and out is supplied to connected devices on pin P3.3/UCLK0 (in slave mode).

#### port P3, P3.4, and P3.5 input/output with Schmitt-trigger



PnSel.x	PnDIR.x	DIRECTION CONTROL FROM MODULE	PnOUT.x	MODULE X OUT	PnIN.x	MODULE X IN
P3Sel.4	P3DIR.4	Vcc	P3OUT.4	UTXD0†	P3IN.4	Unused
P3Sel.5	P3DIR.5	V <sub>SS</sub>	P3OUT.5	V <sub>SS</sub>	P3IN.5	URXD0 <sup>‡</sup>

<sup>†</sup>Output from USART0 module



<sup>‡</sup> Input to USART0 module

#### APPLICATION INFORMATION

#### JTAG fuse check mode

MSP430 devices that have the fuse on the TEST terminal have a fuse check mode that tests the continuity of the fuse the first time the JTAG port is accessed after a power-on reset (POR). When activated, a fuse check current,  $I_{TF}$ , of 1 mA at 3 V, 2.5 mA at 5 V can flow from the TEST pin to ground if the fuse is not burned. Care must be taken to avoid accidentally activating the fuse check mode and increasing overall system power consumption.

When the TEST pin is taken back low after a test or programming session, the fuse check mode and sense currents are terminated.

Activation of the fuse check mode occurs with the first negative edge on the TMS pin after power up or if TMS is being held low during power up. The second positive edge on the TMS pin deactivates the fuse check mode. After deactivation, the fuse check mode remains inactive until another POR occurs. After each POR the fuse check mode has the potential to be activated.

The fuse check current will only flow when the fuse check mode is active and the TMS pin is in a low state (see Figure 10). Therefore, the additional current flow can be prevented by holding the TMS pin high (default condition).

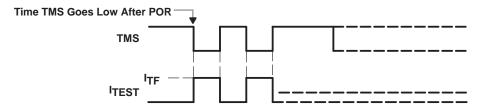


Figure 10. Fuse Check Mode Current, MSP430F11x2, MSP430F12x2

The JTAG pins are terminated internally, and therefore do not require external termination.

#### NOTE:

The CODE and RAM data protection is ensured if the JTAG fuse is blown and the 256-bit bootloader access key is used. Also, see the *bootstrap loader* section for more information.

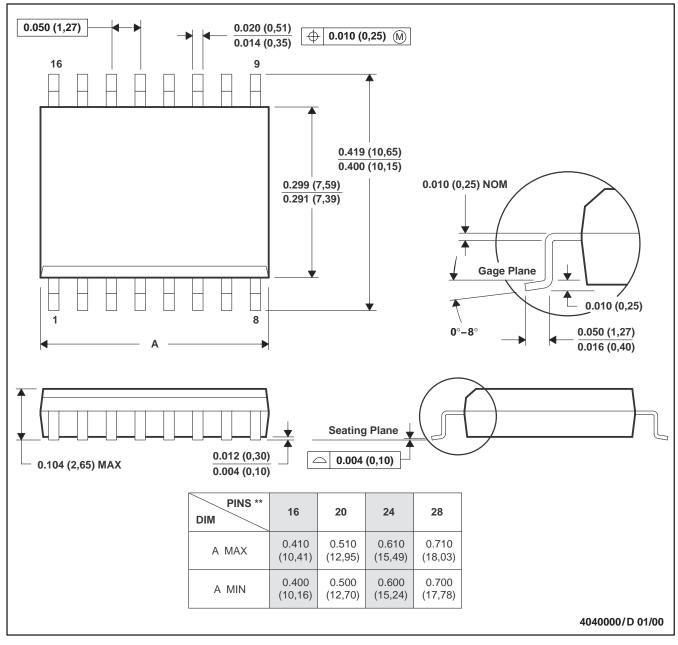


# **MECHANICAL DATA**

# DW (R-PDSO-G\*\*)

#### **16 PINS SHOWN**

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

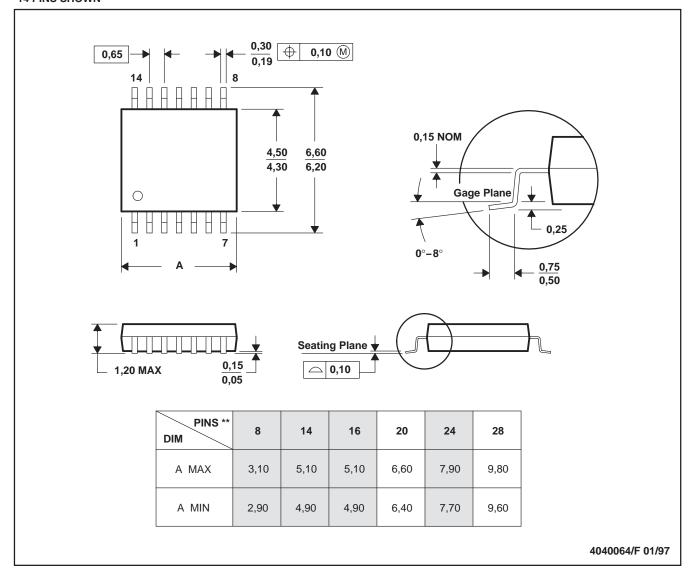
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013



# PW (R-PDSO-G\*\*)

#### 14 PINS SHOWN

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

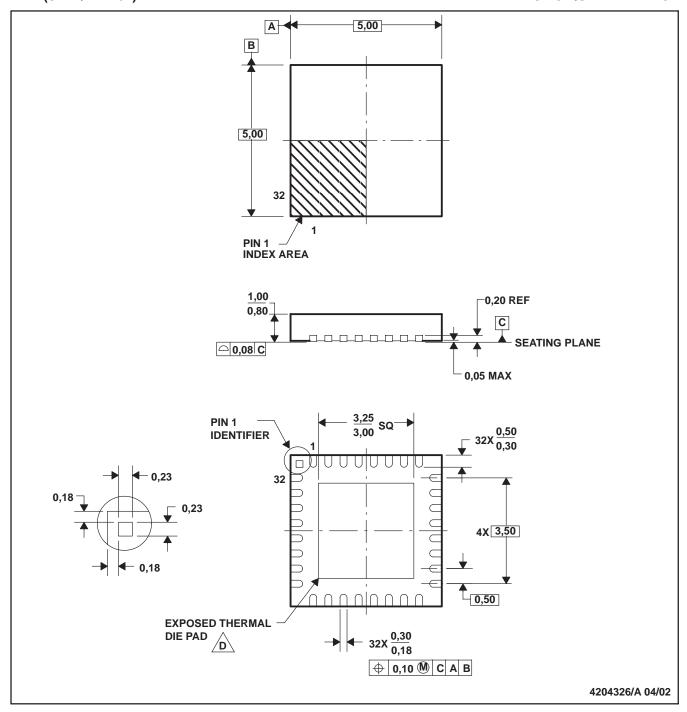
B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

# RHB (S-PQFP-N32)

#### PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

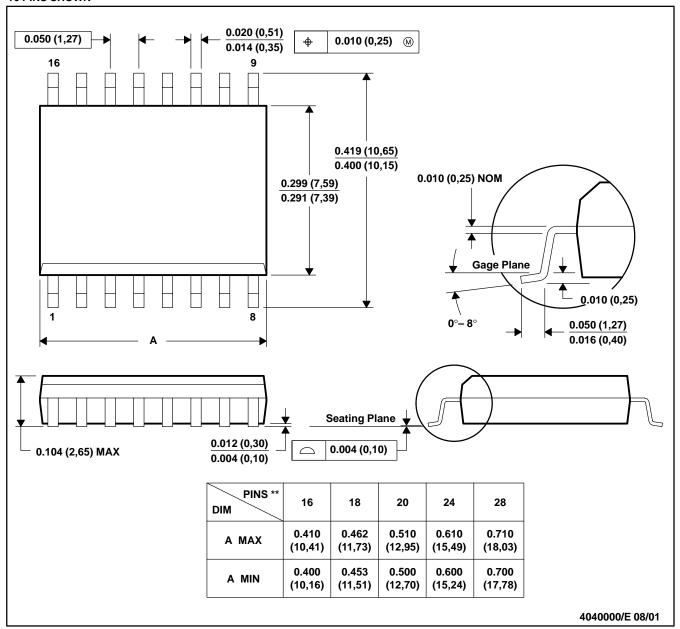
- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) Package configuration.
- D. The Package thermal performance may be enhanced by bonding the thermal die pad to an external thermal plane. This pad is electrically and thermally connected to the backside of the die and possibly selected ground leads.
- E. Falls within JEDEC MO-220.



# DW (R-PDSO-G\*\*)

#### PLASTIC SMALL-OUTLINE PACKAGE

#### **16 PINS SHOWN**



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-013

# PW (R-PDSO-G\*\*)

#### 14 PINS SHOWN

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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Mailing Address: Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

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